

Notice of References Cited	Application/Control No. 10/542,171	Applicant(s)/Patent Under Reexamination TANAKA ET AL.	
	Examiner Karie O'Neill Apicella	Art Unit 1795	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0194589	10-2003	Pratt et al.	429/22
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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NON-PATENT DOCUMENTS

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